

<b>Notice of References Cited</b>	Application/Control No. <b>10/077,146</b>	Applicant(s)/Patent Under Reexam <b>Chen et al.</b>	
	Examiner <b>Edward Pipala</b>	Art Unit <b>3661</b>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
A	5,657,231	8/1997	Nobe et al.	701	209
B	6,269,303	7/2001	Watanabe et al.	701	209
C					
D					
E					
F					
G					
H					
I					
J					
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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